

TOSHIBA Bipolar Linear Integrated Circuit Silicon Monolithic

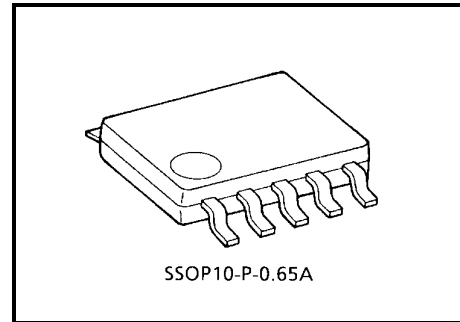
TA6009FN, TA6009FNG

Shock Sensor IC (1 ch version)

TA6009FN/FNG detects an existence of external shock through the shock sensor and output.

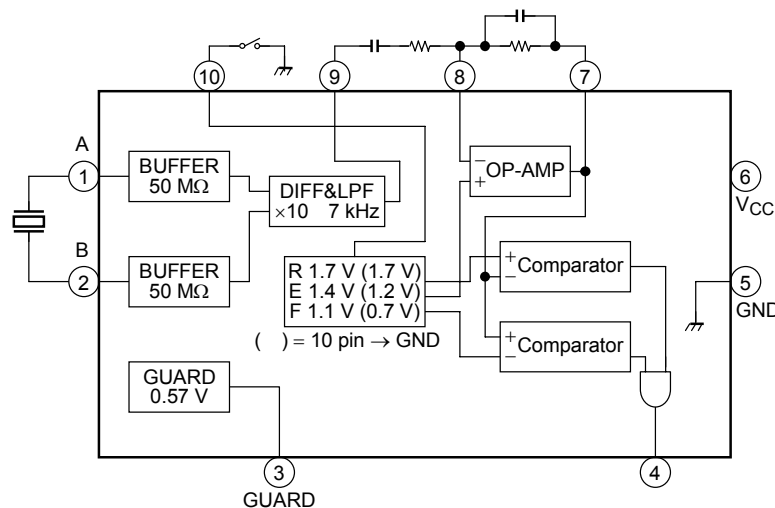
Features

- TA6009FN/FNG operates from 2.7 to 5.5 V DC single power supply voltage.
- Signal from the shock sensor is amplified according to setting gain, and is detected through the internal window comparator.
- TA6009FN/FNG incorporates 1-ch shock detecting circuitry.
- Input terminal of sensor signal is designed high impedance.
Differential input impedance = 100 MΩ (typ.)
- LPF (low pass filter) circuitry is incorporated.
Cut-off frequency of LPF = 7 kHz
- Sensitivity of shock detection can be adjusted by external devices.
- Small package
SSOP10-P-0.65A (0.65 mm pitch)

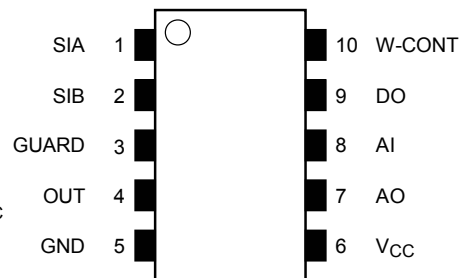


Weight: 0.04 g (typ.)

Block Diagram



Pin Connection (top view)



Pin Function

Pin No.	Pin Name	Function
1	SIA	Connection terminal of shock sensor
2	SIB	Connection terminal of shock sensor
3	GUARD	Input (1, 2 pin) GUARD terminal
4	OUT	Output terminal (output = "L" when shock is detected.)
5	GND	Ground terminal
6	V _{CC}	Power supply voltage
7	AO	Op-Amp output terminal
8	AI	Op-Amp input terminal
9	DO	Differential-Amp output terminal
10	W-CONT	WindComp. trip voltage selection terminal

Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Power supply voltage	V _{CC}	7	V
Power dissipation	P _D	300	mW
Storage temperature	T _{stg}	-55 to 150	°C

Recommend Operating Condition

Characteristics	Symbol	Rating	Unit
Power supply voltage	V _{CC}	2.7 to 5.5	V
Operating temperature	T _{opr}	-25 to 85	°C

Electrical Characteristics (unless otherwise specified, $V_{CC} = 3.3\text{ V}$, $T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Supply voltage	V_{CC}	—	—	2.7	3.3	5.5	V
Supply current	I_{CC}	(1)	$V_{CC} = 3.3\text{ V}$		1.8	2.4	mA
			$V_{CC} = 5.0\text{ V}$		1.8	2.4	

(GUARD)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Output voltage	V_{oGur}	(2)	—	0.52	0.57	0.62	V

(DIFF-AMP)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Input impedance (Note 1)	Z_{in}	—	—	50	100		$M\Omega$
Gain	G_{vBuf}	(3)	—	19.6	20	20.4	dB
Output DC voltage	V_{oBuf}	(4)	Connect C = 100 pF between 1 pin and 2 pin	0.7	1	1.3	V
Low pass filter cut-off freq.	f_c	(5)	Frequency at -3dB point	5	7	10	kHz
Output source current	I_{Bso}	(6)	$V_{oh} = V_{CC} - 1\text{ V}$	400	800		μA
Output sink current	I_{Bsi}	(7)	$V_{ol} = 0.3\text{ V}$	75	130		μA

Note 1: Marked parameters are reference data.

(OP-AMP)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Cut-off frequency (Note 1)	f_T	—	—	1.5	2		MHz
Openloop gain (Note 1)	G_{vo}	—	—	80	90		dB
Input voltage 1	V_{in1}	(8)	10 pin → OPEN (Note 2)	1.33	1.4	1.47	V
Input voltage 2	V_{in2}	(9)	10 pin → GND (Note 2)	1.14	1.2	1.26	V
Input current	I_{in}	(10)	—		25	50	nA
Offset voltage (Note 1)	V_{off}	—	—	-5	0	5	mV
Output source current	I_{Aso}	(11)	$V_{oh} = V_{CC} - 1\text{ V}$	300	800		μA
Output sink current	I_{Asi}	(12)	$V_{ol} = 0.3\text{ V}$	130	200		μA

Note 1: Marked parameters are reference data.

Note 2: 10 pin must be non-connected otherwise connected to GND.

(window-comparator)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Trip voltage 1 (Note 1)	V_{trp1}	—	10 pin → OPEN (Note 2)	$V_{in1} \pm 0.285$	$V_{in1} \pm 0.3$	$V_{in1} \pm 0.315$	V
Trip voltage 2 (Note 1)	V_{trp2}	—	10 pin → GND (Note 2)	$V_{in2} \pm 0.475$	$V_{in2} \pm 0.5$	$V_{in2} \pm 0.525$	V
Output source current	I_{Wso}	(13)	$V_{oh} = V_{CC} - 0.5\text{ V}$	30	50		μA
Output sink current	I_{Wsi}	(14)	$V_{ol} = 0.3\text{ V}$	300	800		μA

Note 1: Marked parameters are reference data.

Note 2: 10 pin must be non-connected otherwise connected to GND.

Application Note

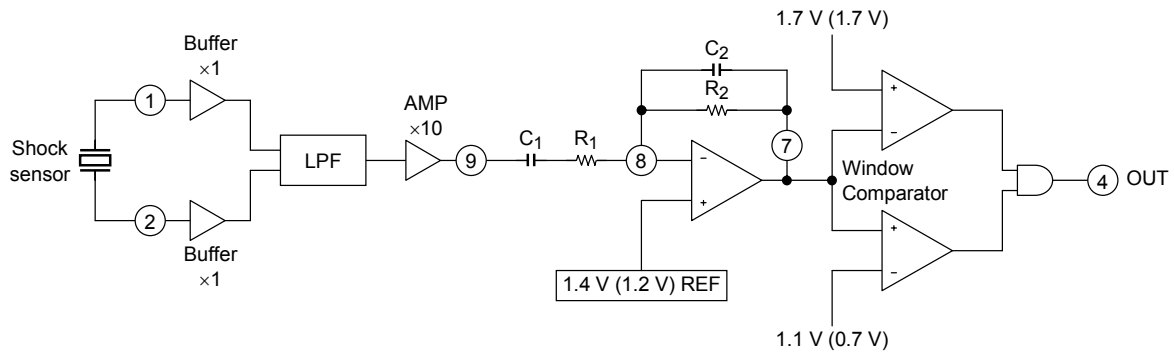


Figure 1 The Composition of G-Force Sense Amplifier

Figure 1 is the composition of G-Force sense amplifier.

The shock sensor is connected between 1 and 2 terminal.

When G-force Sensor (sensor sensibility = s (mV/G)) is used to detect external shock of g (G), the external parts are determined as following.

(gain setting) * 10 PIN → GND

$$500/(s \times g) = G1$$

$$G1/10 = G \text{ (OP-AMP)}$$

(HPF setting)

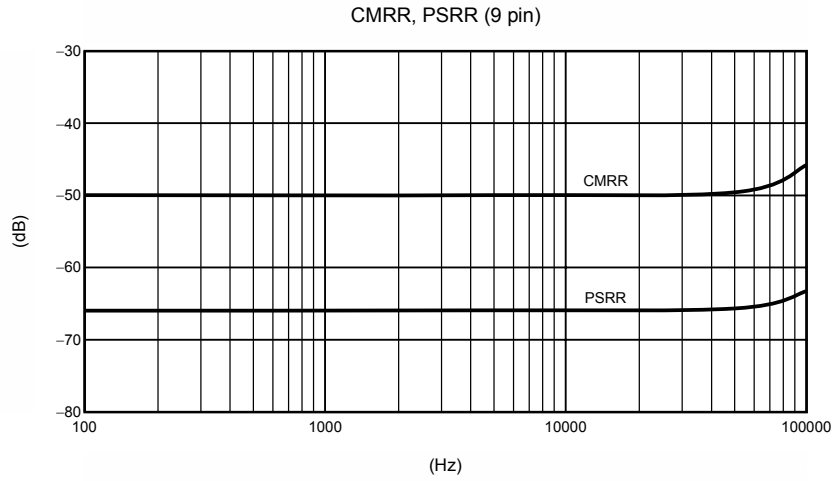
$$f_c = 1/(2 \pi \times R_1 \times C_1)$$

(LPF setting)

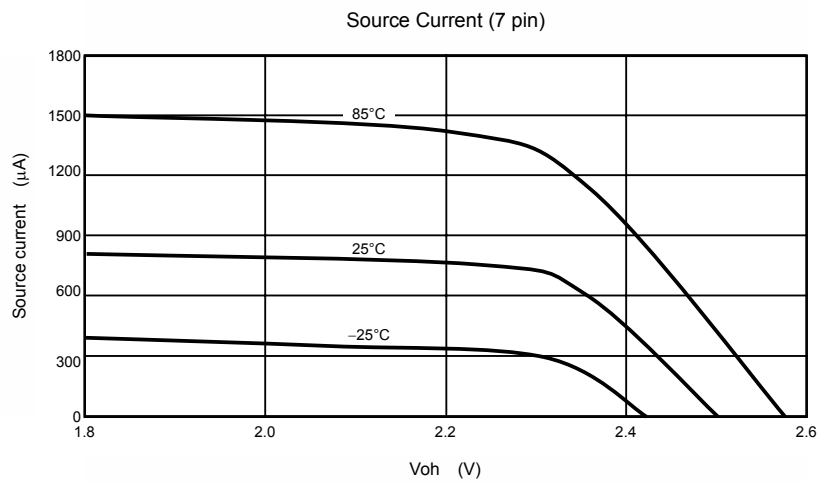
$$f_c = 1/(2 \pi \times R_2 \times C_2)$$

Reference Data

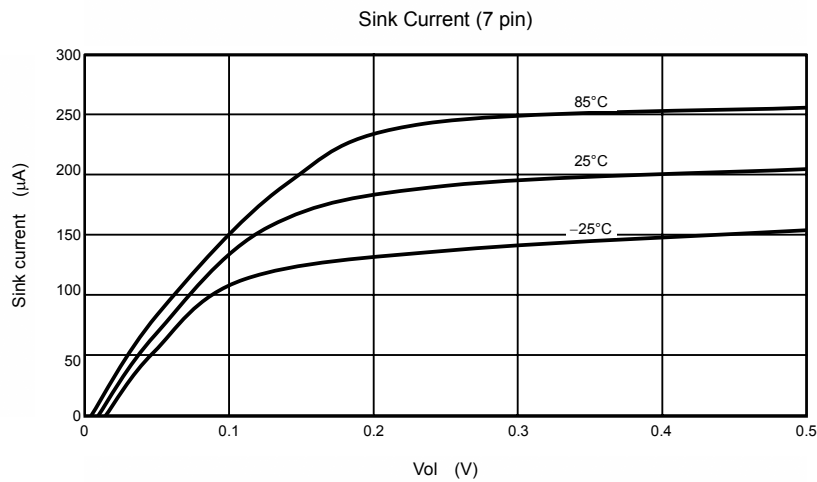
- (1) 9 pin (DIFF-AMP output) CMRR, PSRR



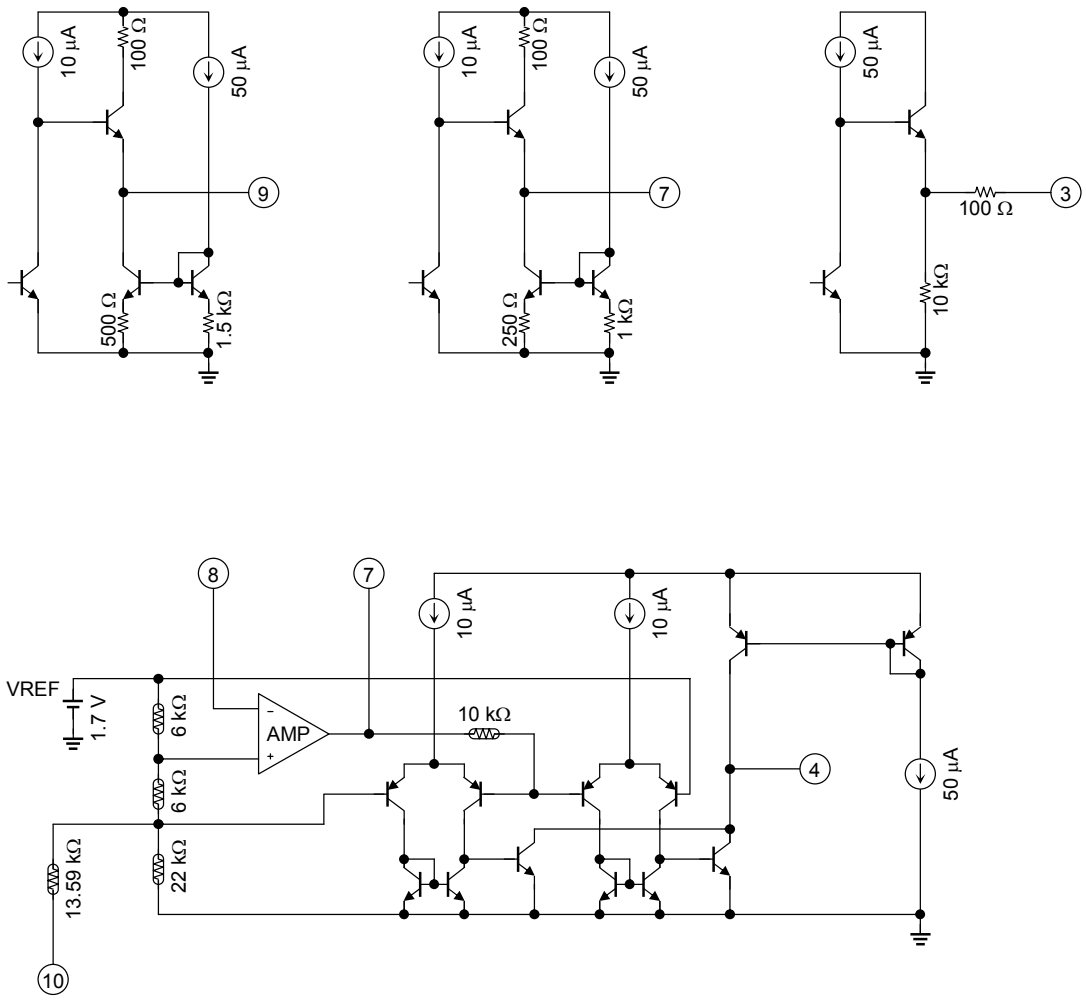
- (2) 7 pin (OP-AMP output) source current



- (3) 7 pin (OP-AMP output) sink current

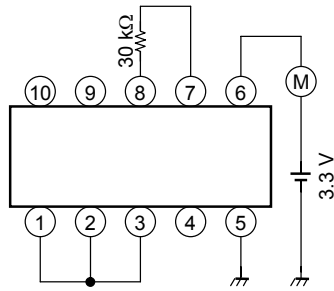


Equivalent Circuit

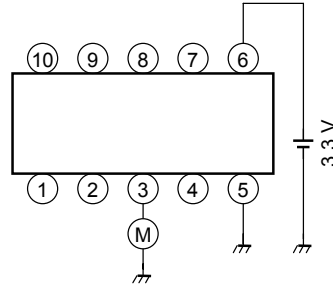


Test Circuit

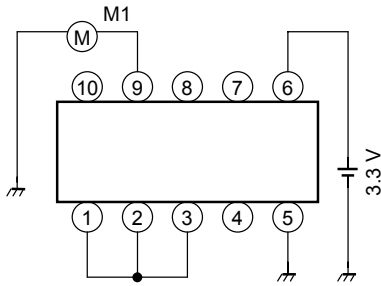
(1) Supply current **ICC**



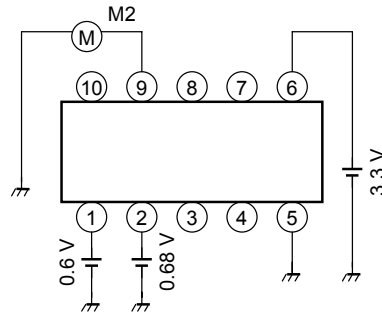
(2) GUARD
Output voltage **VoGur**



(3) DIFF-AMP
Gain **GvBuf**
Step 1

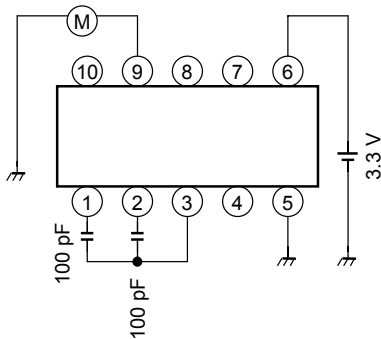


Step 2

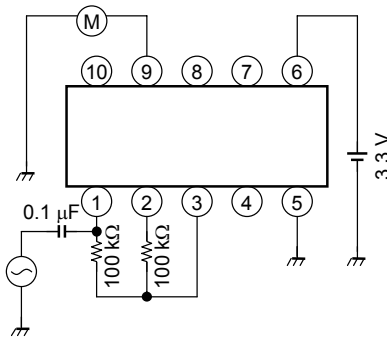


$$\text{Gain} = \frac{M2 - M1}{0.68 - 0.60}$$

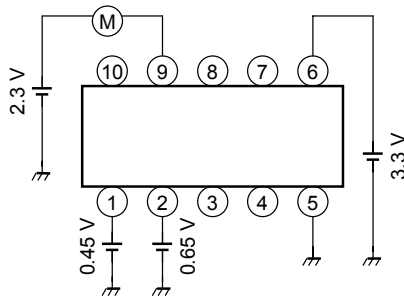
(4) DIFF-AMP
Output DC voltage **VoBuf**



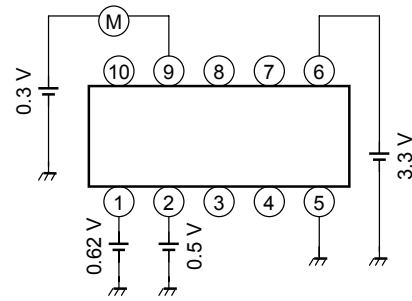
(5) DIFF-AMP
Low pass filter cut-off freq. **fc**



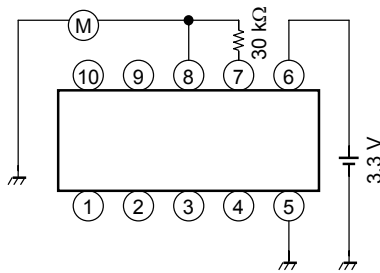
(6) DIFF-AMP
Output source current I_{Bso}



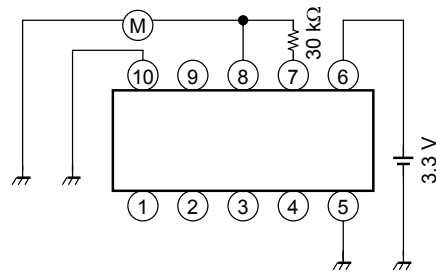
(7) DIFF-AMP
Output sink current I_{Bsi}



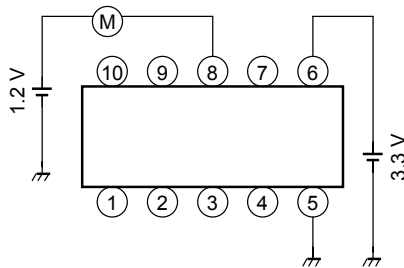
(8) OP-AMP
Input voltage 1 V_{in1}



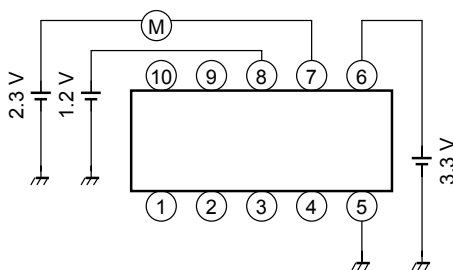
(9) OP-AMP
Input voltage 2 V_{in2}



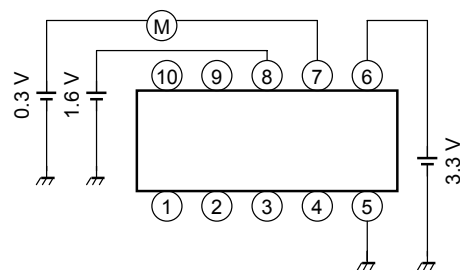
(10) OP-AMP
Input current I_{in}



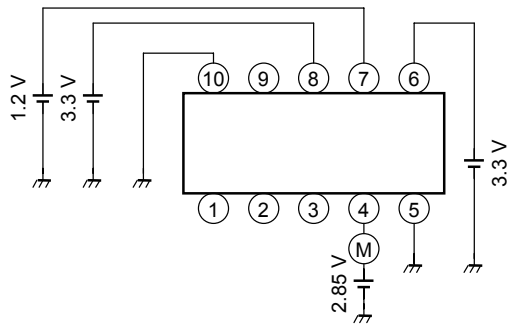
(11) OP-AMP
Output source current I_{Aso}



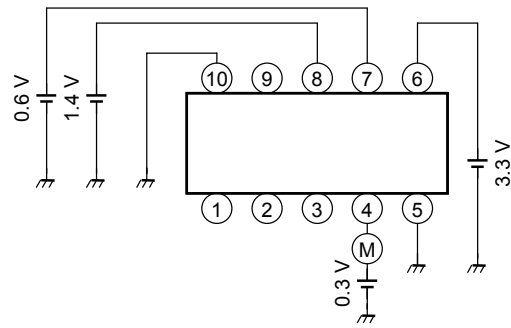
(12) OP-AMP
Output sink current I_{Asi}



(13) Window comparator
Output source current I_{Wso}

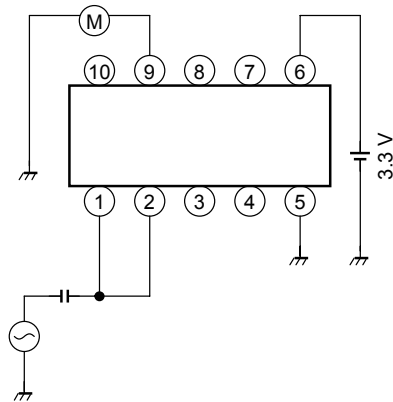


(14) Window comparator
Output sink current I_{Wsi}

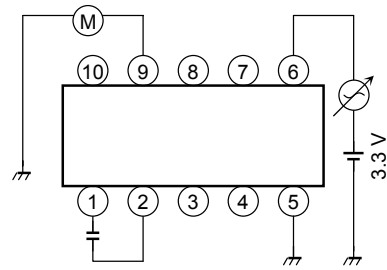


Test Circuit (for reference)

(a) DIFF-AMP
CMRR



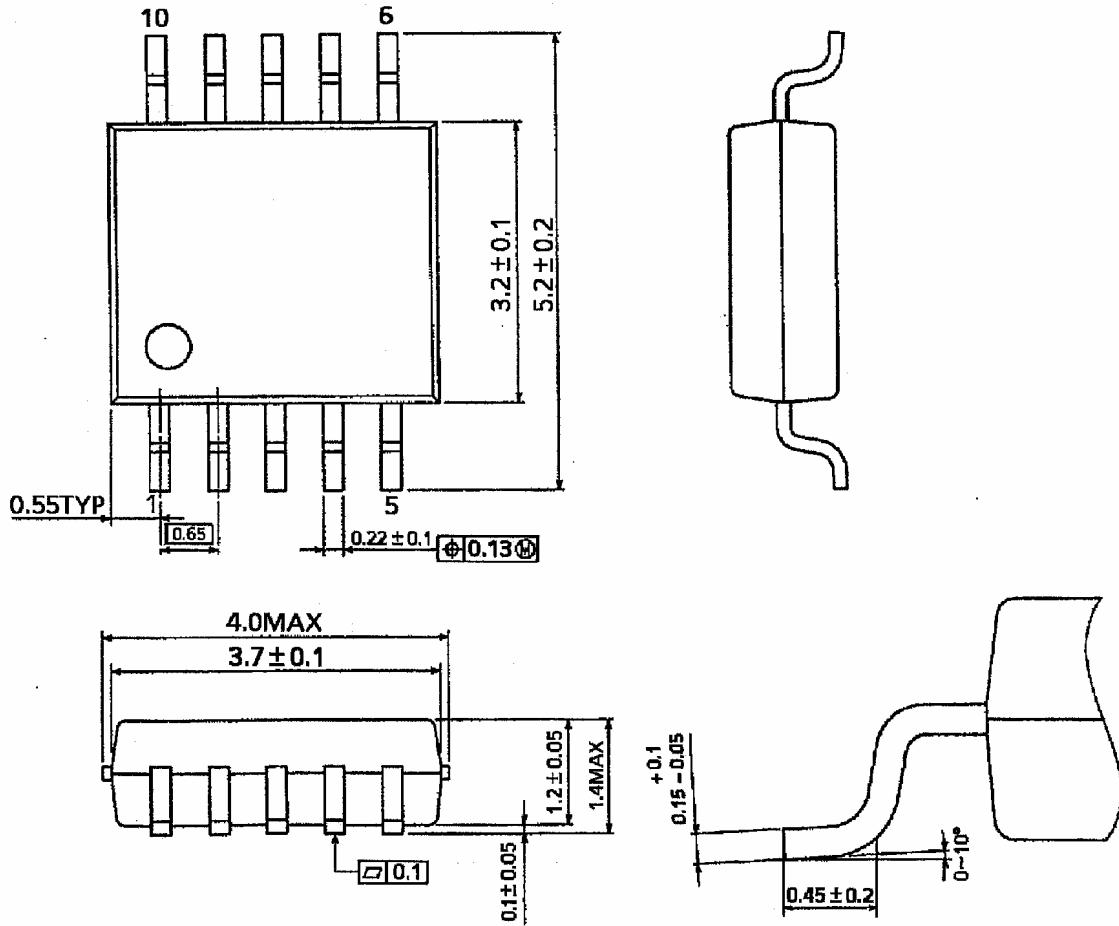
(b) DIFF-AMP
PSRR



Package Dimensions

SSOP10-P-0.65A

Unit : mm



Weight: 0.04 g (typ.)

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